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Deep Learning for Computer Vision: Algorithms, Theory and Application

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Message from the Collection Editors

This Special Issue aims at bringing together researchers and scientists from various disciplines to present recent advances in dealing with the challenging problems of computer vision within the framework of deep learning. We invite authors to submit manuscripts on topics related to the theme of the Special Issue and which have not been previously published. The topics of interest include, but are not limited to:

- Deep learning algorithms and models (supervised/weakly supervised/unsupervised)
- Feature learning and feature representation based on deep learning
- Deep learning-based image recognition
- Deep learning-based video understanding
- Deep learning-based remote sensing image analysis
- Deep learning-based saliency/co-saliency detection
- Deep learning-based visual object tracking
- Deep learning-based image super-resolution
- Deep learning-based image quality assessment
- Deep network compression and acceleration

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Message from the Editor-in-Chief

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